

CONFERENCE VENUE

The conference is organized at the historic Stadscampus of University of Antwerp (<http://www.ua.ac.be>) situated in the city center of Antwerp.

Travel instructions are available on the conference website or with the conference secretariat.

REGISTRATION FEE

Before 16 February 2012:

- 250 EUR for regular participants
- 200 EUR for students

From 16 February till 26 March 2012:

- 350 EUR for regular participants
- 300 EUR for students

The fee includes:

two-day access to all sessions, exhibition, coffee breaks, and lunch on both days.

After 26 March 2012:

- 350 EUR for regular participants
- 300 EUR for students

The fee includes:

two-day access to all sessions, exhibition, coffee breaks, but *no guaranteed lunches*.

OPTIMESS2012 ON THE WEB

All information on the technical program, registration and abstract submission forms, accomodation etc. can be found on the conference web page:

<http://OPTIMESS2012.ua.ac.be>

Contact the conference secretariat at:

OPTIMESS2012@ua.ac.be



University of Antwerp – Stadscampus – Building B
Prinsstraat 13 - 2000 Antwerp - Belgium



IMPORTANT DATES

- Abstract submission deadline:
20 December 2011
- Notification of abstract acceptance:
10 February 2012
- Early registration deadline:
16 February 2012
- Actual conference dates:
4 & 5 April 2012

OPTIMESS

2012

CALL FOR PAPERS

**5th International
Conference on
Optical Measurement
Techniques for
Structures & Systems**

4 & 5 April 2012

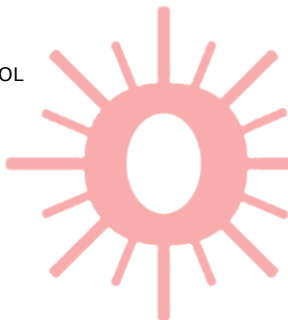
Antwerp – Belgium



CONFERENCE TOPICS

Papers are solicited on research results and applications in the following areas:

- DIGITAL IMAGE CORRELATION
- LASER DOPPLER VIBROMETRY
- FLOW VISUALIZATION: PARTICLE IMAGING, VELOCIMETRY, LASER DOPPLER ANEMOMETRY
- ELECTRONIC SPECKLE PATTERN INTERFEROMETRY
- HOLOGRAPHY
- SHEAROGRAPHY
- MOIRÉ PROFILOMETRY, STRUCTURED LIGHT PROJECTION TECHNIQUES
- STEREOSCOPY
- OPTICAL FIBRE SENSORS
- LASER SCANNERS
- CCD-LED MEASUREMENTS
- INFRARED THERMOGRAPHY
- SIGNAL AND IMAGE PROCESSING
- MODELLING FROM OPTICAL MEASUREMENT DATA
- LASER ULTRASONICS
- DIMENSIONAL METROLOGY
- VIBRATION MEASUREMENTS
- PHOTOELASTICITY
- NONDESTRUCTIVE TESTING
- MIRCOMEASUREMENTS
- PROCESS MONITORING
- (IN-LINE) QUALITY CONTROL
- AUTOMOTIVE ENGINEERING
- AEROSPACE ENGINEERING
- BIOMEDICAL RESEARCH
- (MICRO) ELECTRONICS ENGINEERING
- LARGE-SCALE VIBRATIONS IN CIVIL ENGINEERING
- DAMAGE DETECTION
- MATERIAL CHARACTERIZATION
- ...
- CALIBRATION
- PRODUCTION CONTROL
- ...



ACCOMODATION

The historic city center of Antwerp is packed with hotels of any price range. A special conference rate is given by the IBIS hotel. More info on the webpage.

KEYNOTE LECTURES

- Prof. Jonathan Huntley (UK)
- Prof. Wolfgang Osten (DE)
- Prof. Chandra Shakher (IN)
- Prof. Mitsuo Takeda (JP)

ORGANIZING COMMITTEE

- Prof. Joris Dirckx (UA)
- Dr. Jan Buytaert (UA)
- Prof. Roel Baets (UGent - IMEC)
- Prof. Wim Van Paepegem (UGent)

SCIENTIFIC COMMITTEE

- Asundi Anand (SG)
- Hack Erwin (CH)
- Huntley Jonathan (UK)
- Mendoza-Santoyo Fernando (MX)
- Osten Wolfgang (DE)
- Patorski Krzysztof (PL)
- Pedrini Giancarlo (DE)
- Pinotti Barbosa Marcos (BR)
- Rastogi Pramod (CH)
- Rodriguez-Vera Ramon (MX)
- Rothberg Steve (UK)
- Shakher Chandra (IN)
- Takeda Mitsuo (JP)
- Tutsch Rainer (DE)
- Baets Roel (BE)
- Buytaert Jan (BE)
- De Roeck Guido (BE)
- Dirckx Joris (BE)
- Glorieux Christ (BE)
- Guillaume Patrick (BE)
- Kruth Jean-Pierre (BE)
- Lomov Stepan (BE)
- Lava Pascal (BE)
- Lecompte David (BE)
- Van Paepegem Wim (BE)
- Vanlanduit Steve (BE)



Antwerp – Belgium – Europe

EXHIBITION

An interesting exhibition in conjunction with the conference will provide a unique opportunity for all participants to gain hands-on experience with the newest and most advanced optical measurement instrumentation products.

